

Patent Assignment Abstract of Title

Total Assignments: 2

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PCT #: NONE **Publication #:** NONE **Pub Dt:**

Inventors: Scott Williams, Alan Schachtely

Title: Custom rule system and method for expert systems

Assignment: 1

Reel/Frame: <u>011907/0654</u>	Received: 06/22/2001	Recorded: 06/14/2001	Mailed: 08/29/2001	Pages: 4
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Conveyance: ASSIGNMENT OF ASSIGNORS INTEREST (SEE DOCUMENT FOR DETAILS).

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Exec Dt: 09/18/2000

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Exec Dt: 09/18/2000

Assignee: BENTLY NEVADA CORPORATION

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Assignment: 2

Reel/Frame: <u>013033/0090</u>	Received: 07/02/2002	Recorded: 06/25/2002	Mailed: 08/29/2002	Pages: 7
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Conveyance: ASSIGNMENT OF ASSIGNORS INTEREST (SEE DOCUMENT FOR DETAILS).

Assignor: BENTLY NEVADA CORPORATION

Exec Dt: 04/30/2002

Assignee: BN CORPORATION, LLC

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